

Nonequilibrium charge transport and current noise in quantum SINIS contacts

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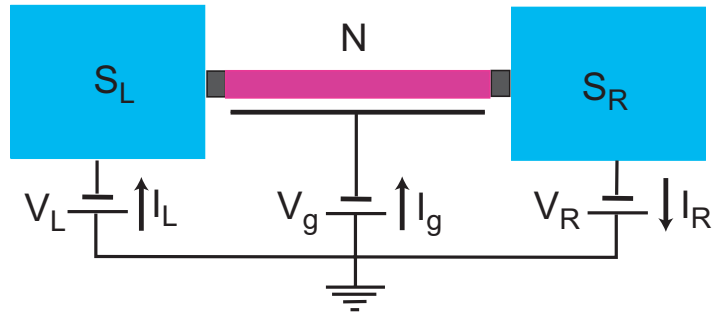
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Outline

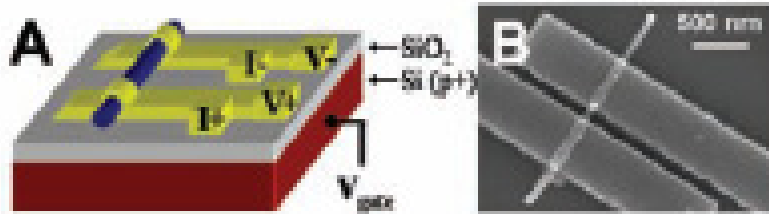
- ◆ **Excitation spectrum in quantum SINIS junctions.**
- ◆ **Kinetic equation in presence of Landau-Zener transitions and inelastic relaxation**
- ◆ **Non-equilibrium DC current**
- ◆ **Current noise**

Quantum SINIS junctions



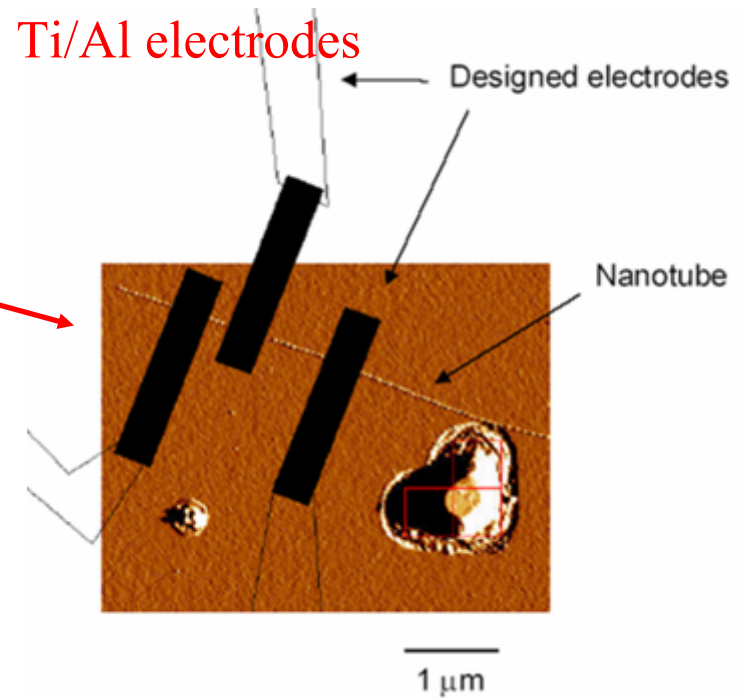
Possible realizations

InAs semiconductor nanowire-
Ti/Al electrodes



Doh *et al.*, *Science* **309**, 272 (2005)

Carbon nanotube-
Ti/Al electrodes

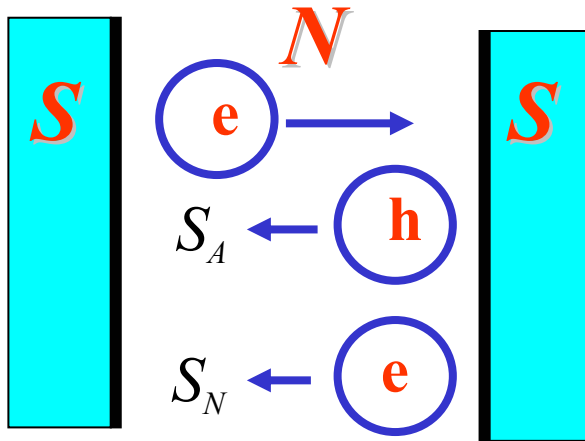


Jarillo-Herrero *et al.*, *Nature* **439**, 953 (2006)

CNT: interlevel distance $\delta\epsilon \approx 3.5$ mV
Superconducting gap: $\Delta \approx 0.25$ mV

Double-barrier SINIS junctions

Interplay between geometrical and Andreev quantization



Amplitude of Andreev reflection = S_A

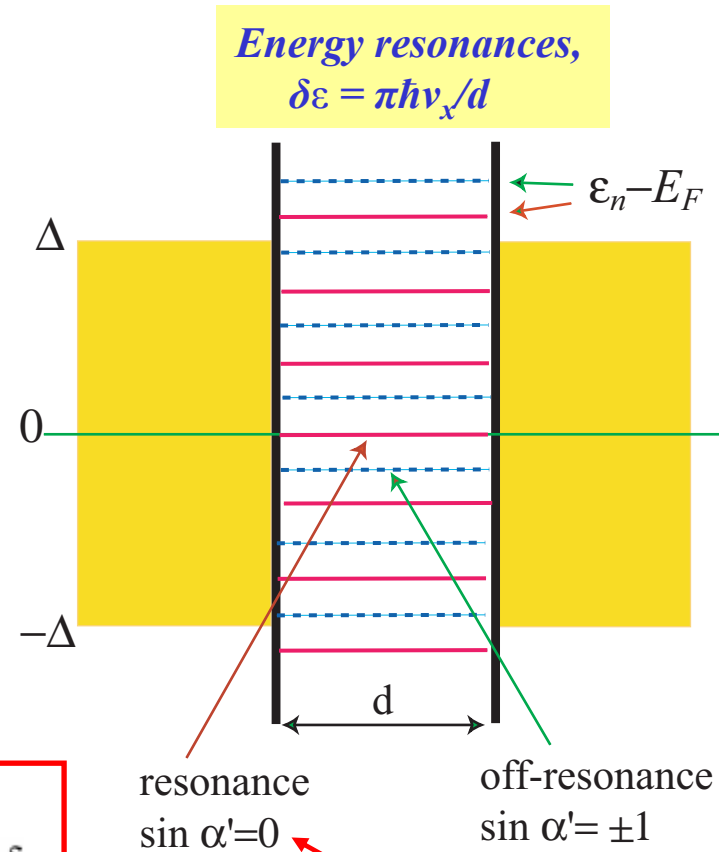
Amplitude of normal reflection = S_N

S_A and S_N depend on energy

Barrier height $U_{1,2} = I\delta(x \pm d/2)$

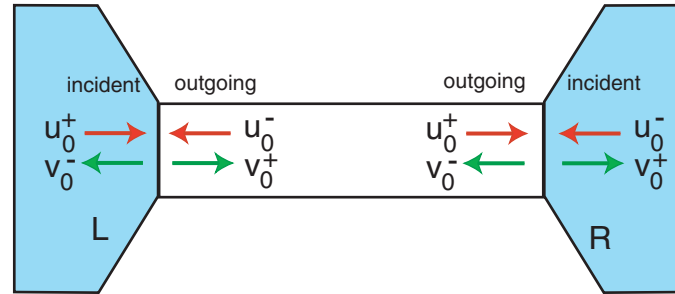
Barrier strength $Z = mI/\hbar^2 k_x$

$$\begin{aligned} \alpha' &= \alpha + \delta \\ \alpha &= k_x d \\ \tan \delta &= 1/Z \end{aligned}$$



One of the resonance levels coincides with the Fermi energy

Scattering matrix approach



The incident and outgoing amplitudes are coupled by \hat{S}_R and \hat{S}_L

$$\begin{pmatrix} u_0^- \\ v_0^+ \end{pmatrix}_R = \hat{S}_R \begin{pmatrix} u_0^+ \\ v_0^- \end{pmatrix}_R, \quad \begin{pmatrix} u_0^+ \\ v_0^- \end{pmatrix}_L = \hat{S}_L \begin{pmatrix} u_0^- \\ v_0^+ \end{pmatrix}_L, \quad \hat{S} = \begin{pmatrix} S_N e^{i\delta} & S_A e^{i\chi} \\ S_A e^{-i\chi} & S_N e^{-i\delta} \end{pmatrix}$$

$$\begin{pmatrix} u_0^\pm \\ v_0^\pm \end{pmatrix}_R = e^{\pm i k_x d} \begin{pmatrix} u_0^\pm \\ v_0^\pm \end{pmatrix}_L$$

The matrix \hat{S} is unitary: $\hat{S}\hat{S}^\dagger = 1$.

Diagonal components of $\hat{S} \Rightarrow$ normal reflection.

Off-diagonal components \Rightarrow Andreev reflection.

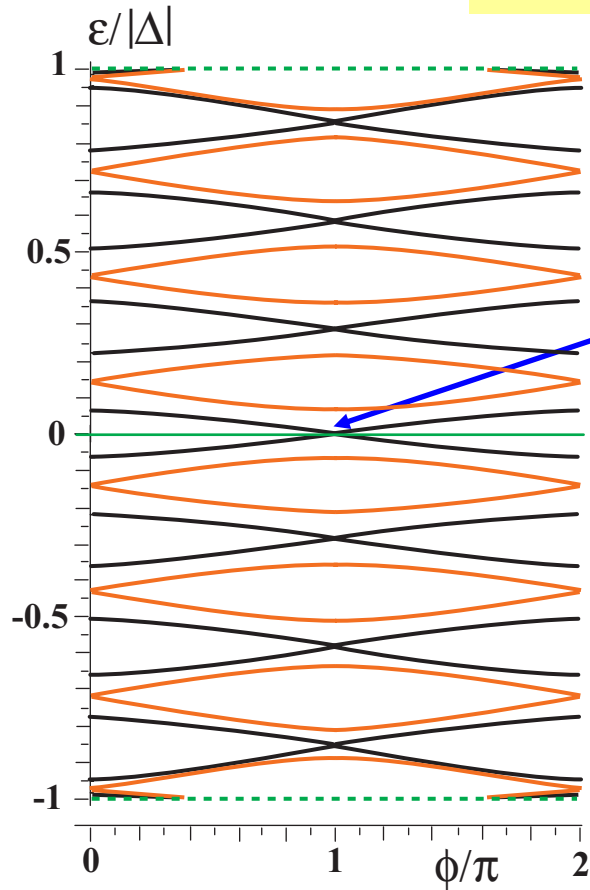
The solvability condition $\Rightarrow \det(1 - e^{i\hat{\sigma}_z k_x d} \hat{S}_R e^{i\hat{\sigma}_z k_x d} \hat{S}_L) = 0$.

Long SINIS junction, $\Delta \gg \delta\varepsilon$

$$\delta\varepsilon = \pi\hbar v_x/d$$

Short SINIS junction, $\Delta \ll \delta\varepsilon$

Number of levels in the contact,
 $N \sim \Delta/\delta\varepsilon \sim d\Delta/\pi\hbar v_x$

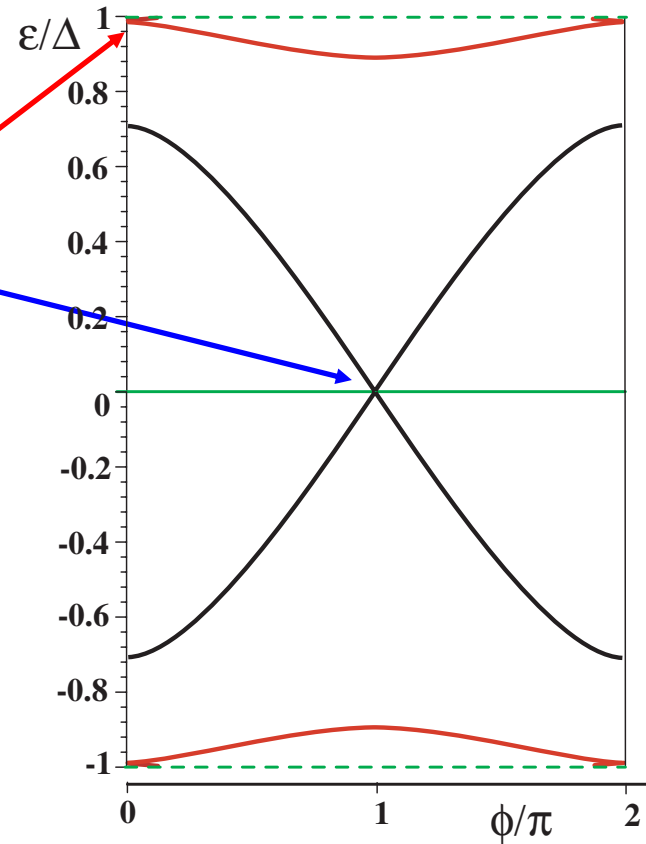


$Z=0.5, d\Delta/\hbar v_x=10.$
Black lines: $\sin \alpha'=0.$
Red lines: $\sin \alpha'=\pm 1$

Gaps are closed

All gaps at $\varphi=\pi$ and $\varphi=0$ disappear for $\sin \alpha'=0$ and $\sin \alpha'=\pm 1$, respectively.

α can be controlled by gate voltage



$Z=1.0, d\Delta/\hbar v_x=0.2.$
Black lines: $\sin \alpha'=0.$
Red lines: $\sin \alpha'=\pm 1$

Sub-gap spectrum of a SINIS junction

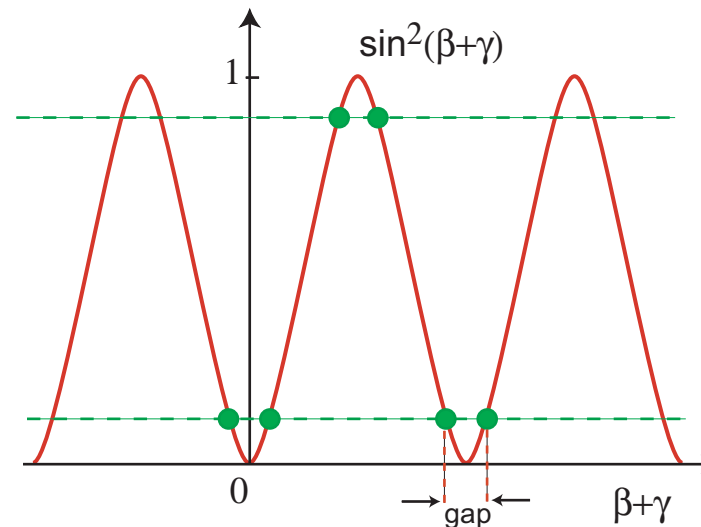
$$|S_N|^2 \sin^2 \alpha' + |S_A|^2 \cos^2(\phi/2) = \sin^2(\beta + \gamma)$$

$$\alpha = k_x d, \quad \beta = \epsilon d / \hbar v_x$$

$$\alpha' = \alpha + \delta, \quad \phi = \chi_2 - \chi_1$$

$$e^{2i\gamma} = S_N / S_N^*$$

$$|S_N|^2 + |S_A|^2 = 1$$



Spectrum in various limits:

e.g., A.Furusaki et al (1992)

Schüssler, Kümmel (1993)

Gogadze, Kosevich (1998)

Shumeiko, Wendin (2000)

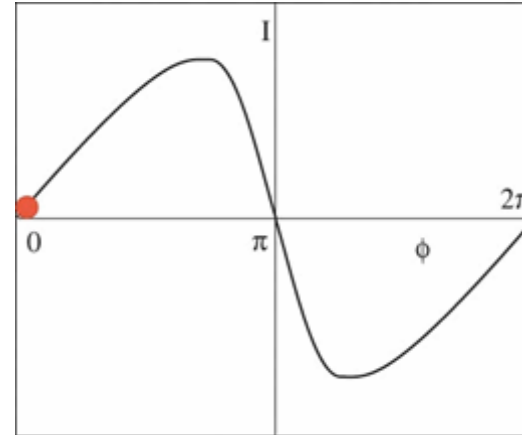
Kuhn et al (2001)

Jakobs, Kümmel (2005)

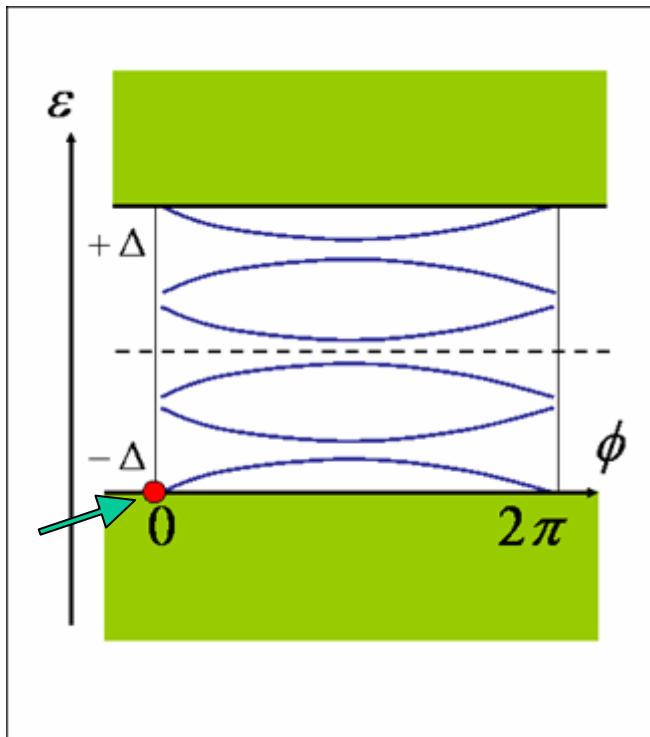
All gaps at $\phi=\pi$ and $\phi=0$
disappear for
 $\sin \alpha'=0$ and $\sin \alpha'=\pm 1$,
respectively

Supercurrent

$$I_s = -\frac{2e}{\hbar} \sum_{\epsilon_n > 0} \frac{\Delta}{\partial \phi} (1 - 2f_n)$$



Example 1: Equilibrium SINIS contact under a small bias $eV \ll \delta\epsilon$



Gaps or strong inelastic relaxation

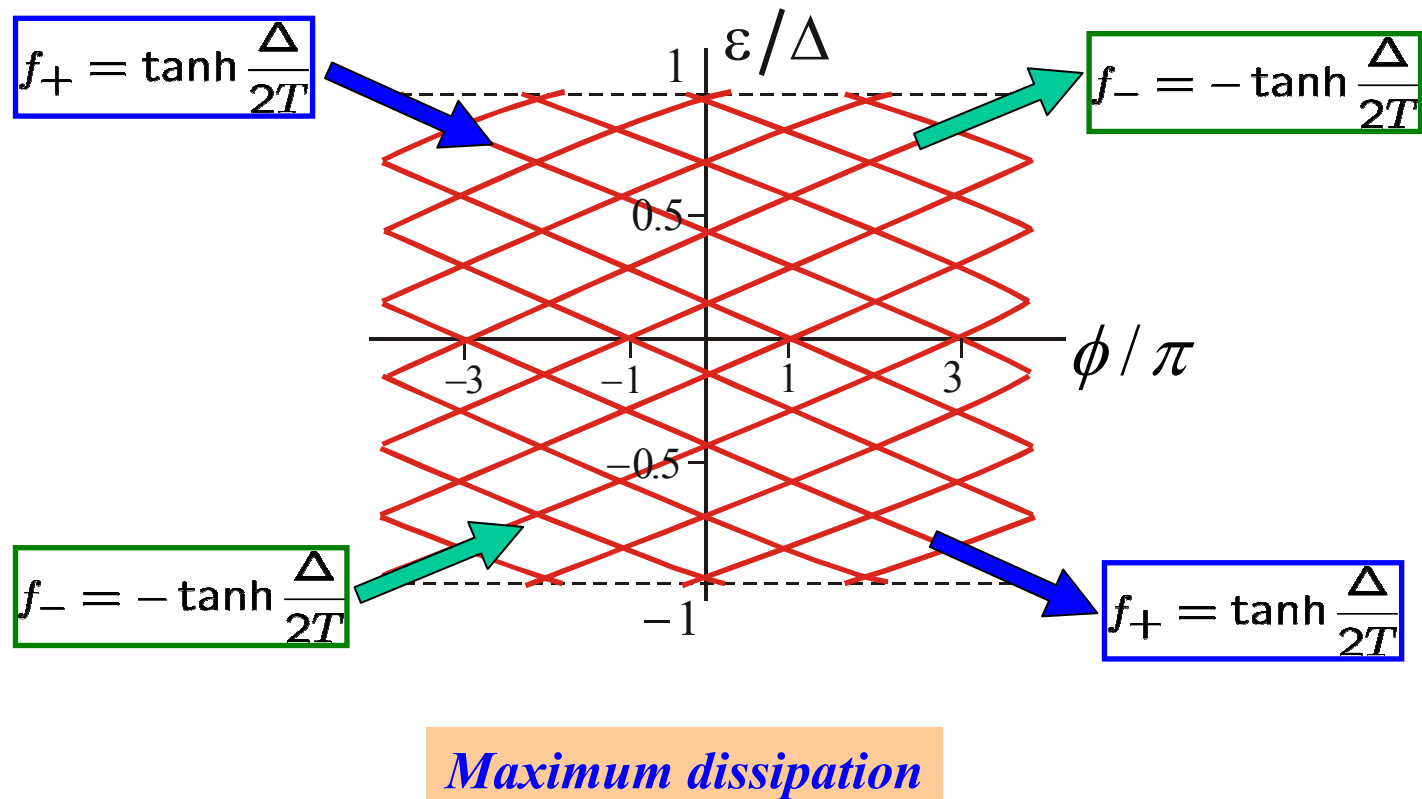
Adiabatic variation along the Andreev levels:

$$d\phi/dt = 2eV/\hbar \equiv \omega_J$$

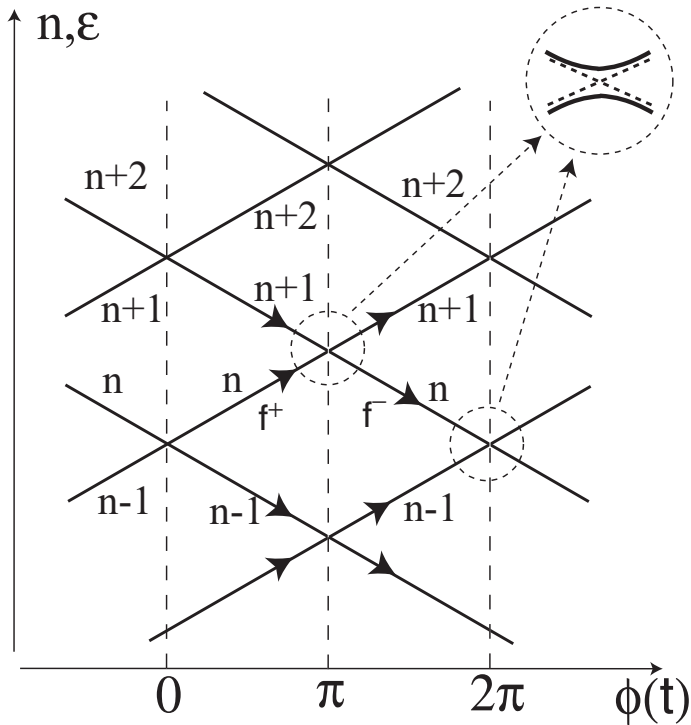
Bloch oscillations of supercurrent

NO dc current without the interlevel Landau-Zener transitions

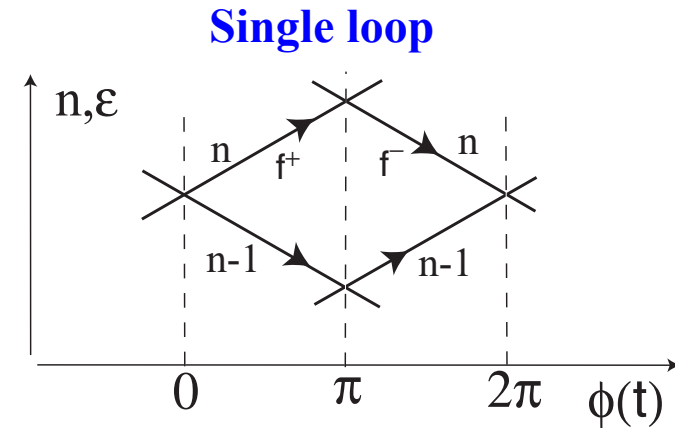
Example 2: Charge transfer for continuous spectral flow



Distribution in the presence of weak inelastic relaxation and voltage-driven Landau-Zener transitions ?



Kinetic equation



$$\frac{1}{\hbar} \int (\epsilon_n - \epsilon_{n-1}) \sim \frac{v_x}{\omega_J d} \gg 1$$

Incoherent inter-level transitions due to the low-voltage condition

$$\begin{aligned} f_n^+(0+) &= p_0 f_{n-1}^+(0-) + (1 - p_0) f_n^-(0-) \\ f_n^-(\pi+) &= p_\pi f_{n+1}^-(\pi-) + (1 - p_\pi) f_n^+(\pi-) \\ f_{n+1}^-(0+) &= p_0 f_{n+2}^-(0-) + (1 - p_0) f_{n+1}^+(0-) \\ f_{n+1}^+(\pi+) &= p_\pi f_n^+(\pi-) + (1 - p_\pi) f_{n+1}^-(\pi-) \end{aligned}$$

Boundary conditions:

$$f_{\epsilon=-|\Delta|}^+ = f^{(0)}(-|\Delta|), \quad f_{\epsilon=+|\Delta|}^- = f^{(0)}(+|\Delta|)$$

Model of weak intra-level inelastic relaxation

$$\frac{\partial f_n}{\partial t} = -\frac{f_n - f_n^{(0)}}{\tau_{\text{in}}}, \quad \tau_{\text{in}} v_x \gg d$$

Low temperatures: $T \ll \hbar v_x / d \Rightarrow f_n^{(0)} = \Theta(-\epsilon_n)$

$$f_n^{\pm} - f_n^{(0)} = C_{\pm} \exp[-r|n|]$$

$$\gamma = \frac{\pi \hbar}{2eV\tau_{\text{in}}} \quad \text{- Degree of inelastic relaxation during Josephson half-period}$$

The effective relaxation rate

Strong inelastic relaxation $\gamma \gg 1 \Rightarrow r \approx \gamma$

Weak inelastic relaxation $\gamma \ll 1$

$$\sinh^2(r) = \gamma(\gamma + p_0 + p_{\pi} - 2p_0 p_{\pi}) / p_0 p_{\pi} .$$

$$r = \begin{cases} \gamma \ll 1, & p_0, p_{\pi} = 1 \\ \gg 1, & p_0, p_{\pi} \rightarrow 0 \end{cases}$$

The distribution function

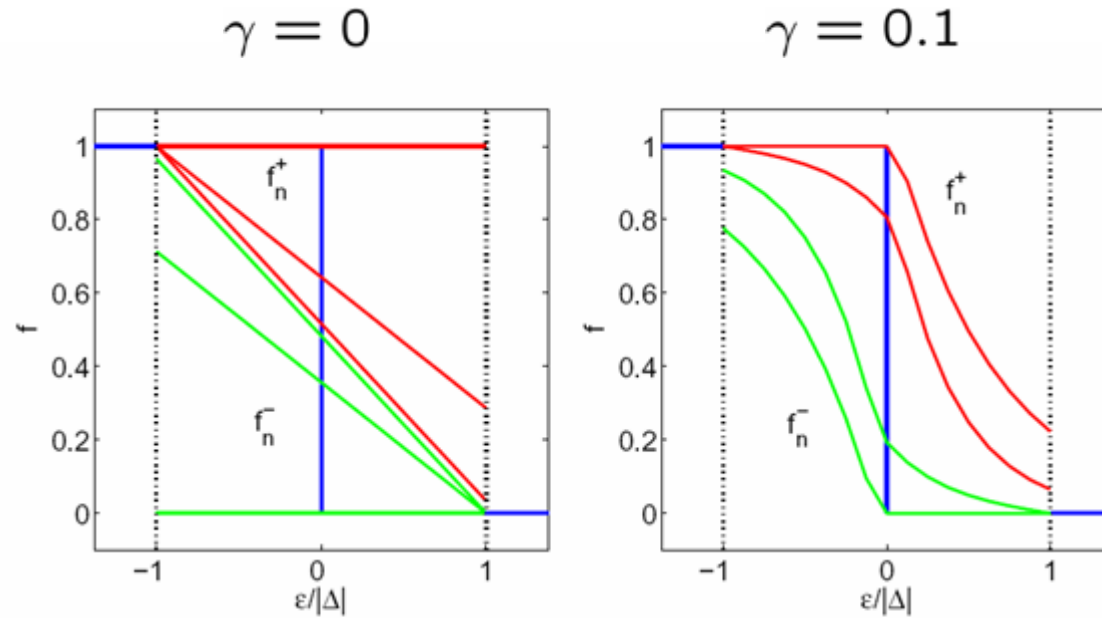


Figure 4.2: Distribution functions for absent, $\gamma = 0$, and small, $\gamma = 0.1$, relaxation on left and right, in this order. Values for tunneling probabilities are $(p_0, p_\pi) = \{(1, 1), (0.9, 0.95), (0.1, 0.1)\}$ from top to bottom for f_n^+ functions (from bottom to top for f_n^-). In the right figure, the last pair is omitted for

Number of excited levels $N_{\text{eff}} = \begin{cases} r^{-1} , & Nr \gg 1 \\ N , & Nr \ll 1 \end{cases}$

Here $N = 2d\Delta/\pi\hbar v_x \gg 1$ is the total number of levels with positive energies

Effective temperature $T_{\text{eff}} = r^{-1}(d\epsilon_n/dn) = (\pi\hbar v_x/2rd)$

DC current

Nonzero average is due to non-equilibrium current carried by the Andreev states

$$\overline{I_{\text{neq}}} = -\frac{2e}{\hbar} \sum_{\epsilon_n > 0}^{\Delta} \overline{\frac{\partial \epsilon_n}{\partial \phi} \tilde{f}_n} = -\frac{ev_x}{d} \sum_{k=1}^{N/2} [\tilde{f}_{2k}^+ - \tilde{f}_{2k-1}^-]$$

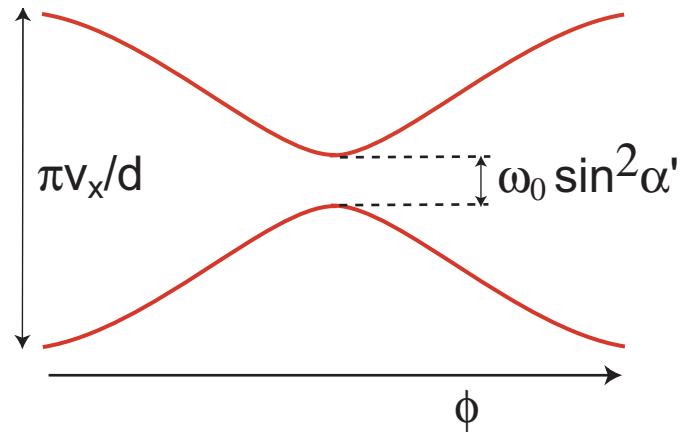
The average current $\bar{I} = \frac{ev_x}{2d} \Phi(p_0, p_\pi)$

For $r \ll 1$

$$\Phi(p_0, p_\pi) = \begin{cases} \frac{2p_0 p_\pi}{(p_0 + p_\pi - 2p_0 p_\pi) + \gamma}, & N\gamma \gg 1 \\ \frac{2p_0 p_\pi}{(p_0 + p_\pi - 2p_0 p_\pi) + 1/N}, & N\gamma \ll 1 \end{cases}$$

The dc current increases when LZ probabilities grow $p_0, p_\pi \rightarrow 1$

LZ probability



$$p_\pi = \exp\left[-\frac{\omega_0}{\omega_J} \sin^2 \alpha'\right]$$
$$p_0 = \exp\left[-\frac{\omega_0}{\omega_J} \cos^2 \alpha'\right]$$

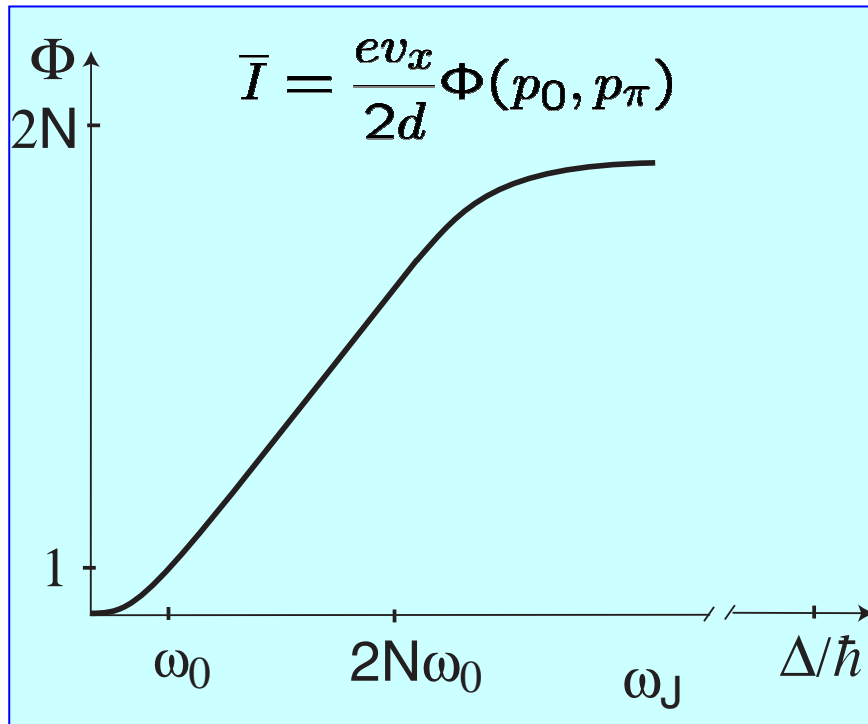
$$\omega_0 = \pi v_x (1 - \mathcal{T}^2) / \mathcal{T} d$$

$$\omega_J = 2eV/\hbar$$

Important: High transparency

$$\omega_0 \ll \pi v_x/d \Rightarrow 1 - \mathcal{T} \ll 1$$

The I-V curve



For $\omega_0 \ll eV/\hbar \ll v_x/d$ when

$$p_0, p_\pi \rightarrow 1$$

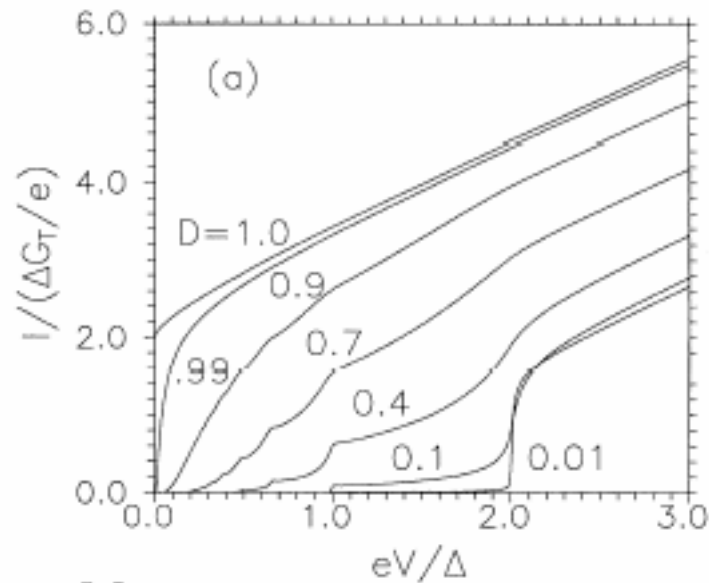
$$\Phi(p_0, p_\pi) \approx \frac{\omega_J}{\omega_0 + \pi/2\tau + \omega_J/2N}$$

The current is N times larger than the critical Josephson current

$$I_c \sim \frac{ev_x}{\pi d}$$

I-V curves. Theory

Point contact, various transparencies D , $T=0$



Averin & Bardas 1995

Long multi-channel bridge, $D=1$

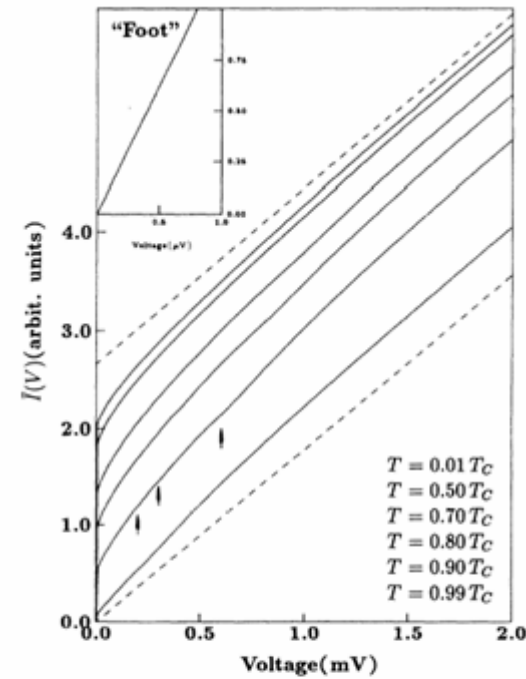


FIG. 1. The solid curves represent the current-voltage characteristics of a SNS junction at different temperatures (the lowest temperature corresponds to the uppermost curve), $\ell_{in}/2a \approx 10^4$. The lower and the upper dashed lines represent the Sharvin current and the extrapolation of the excess current at $T = 0$ K to $V = 0$, respectively. The arrows indicate the subharmonic gap structures at voltages $V_n = 2\Delta(T)/ne$, $n = 1, 2, 3$. The inset shows the steep rise of the current at voltages $V \ll (2a/\ell_{in})\Delta/e$ corresponding to the high-low voltage conductance of Eq. (70), $T = 0$ K.

Gunsenheimer & Zaikin, 1994

Noise spectrum

Spectral density of fluctuations

$$S(\omega) = \int e^{i\omega\tau} d\tau \overline{\left\langle \left\{ \Delta\hat{I}\left(t - \frac{\tau}{2}, x\right), \Delta\hat{I}\left(t + \frac{\tau}{2}, x\right) \right\} \right\rangle}$$

$$\Delta\hat{I} \equiv \hat{I} - \langle \hat{I} \rangle, \quad \{\hat{A}, \hat{B}\} \equiv (\hat{A}\hat{B} + \hat{B}\hat{A})/2$$

$$S(\omega) = -\frac{\pi\hbar^3 e^2}{4m^2} \overline{\sum_{n,m} \delta(\epsilon_n - \epsilon_m + \hbar\omega) L_{nm} [1 - f_1(\epsilon_n) f_1(\epsilon_m)]}$$

Matrix elements in terms of the BdG wave functions

$$L_{nm}(x, t) = \left\{ \left(\nabla_1 - \nabla'_1 \right) \left(\nabla_2 - \nabla'_2 \right) \left[u_n^*(1) u_m(1') \right. \right. \\ \left. \left. + v_n^*(1) v_m(1') \right] \left[u_n(2') u_m^*(2) + v_n(2') v_m^*(2) \right] \right\}_{1=1'=2=2'}$$

Distribution function

$$f_1 = 1 - 2f(\epsilon)$$

Low frequency $\hbar\omega \ll \delta\epsilon \sim \hbar v_x/d$

Only diagonal elements are important

$$S(\omega) = -\frac{\pi\hbar^2 e^2}{8m^2} \delta(\omega) \sum_n \overline{L_{nn} \left[1 - [f_1^{(0)}]^2 - 2f_1^{(0)} \tilde{f}_1 \right]}.$$

Here

$$f_1 = f_1^{(0)} + \tilde{f}_1, \quad f_1^{(0)} = \tanh \frac{\epsilon}{2T}$$

Due to inelastic relaxation

$$\delta(\omega) \Rightarrow \Lambda(\omega) = \frac{1}{2\pi} \frac{\tau^{-1}}{\omega^2 + 1/4\tau^2}$$

Equilibrium thermodynamic noise

High transparency, $Z \rightarrow 0$

$$S_{\text{th}}(\omega) = \frac{\pi v_x^2 e^2}{d^2} \Lambda(\omega) \overline{\sum_{n>0} \cosh^{-2} \frac{\epsilon_n}{2T}}$$

If $\hbar v_x/d \ll T \ll \Delta$,

$$S_{\text{th}}(\omega) = \frac{4T v_x e^2}{\hbar d} \Lambda(\omega) , \quad S_{\text{th}}(0) = \frac{8T e^2 v_x \tau}{\pi \hbar d}$$

Number of excited levels $N_{\text{eff}} = 2Td/\pi \hbar v_x$

Low transparency, $Z \rightarrow \infty$

$$S_{\text{th}}(\omega) = \frac{T v_x e^2}{8Z^8 \hbar d \sin^2(2\alpha')} \Lambda(\omega)$$

Thermodynamic noise: Due to fluctuations in the occupation of Andreev levels.

For point contacts:

Averin & Imam (1996)

Martin-Rodero et al. (1996)

Naveh & Averin (1999)

Non-equilibrium low-voltage noise, $T=0$

$$S(\omega) = -\frac{\pi v_x^2 e^2}{d^2} \delta(\omega) \sum_{k=1}^{N/2} \overline{[f_{2k}^+ + f_{2k-1}^-]}$$

Number of excited levels

$$N_{eff} = \begin{cases} r^{-1}, & 1/N \ll r \ll 1 \\ \sim N, & r \ll 1/N \end{cases}$$

Effective relaxation rate decreases with increase in LZ probabilities

$$r = \sqrt{\frac{\gamma(\gamma + p_0 + p_\pi - 2p_0 p_\pi)}{p_0 p_\pi}}$$

Effective temperature increases with the LZ probabilities

$$T_{eff} = r^{-1} (d\epsilon_n/dn) = (\pi \hbar v_x / 2rd)$$

Zero-frequency noise increases

$$S_{ne}(0) = \frac{8T_{eff} e^2 v_x \tau}{\pi \hbar d}$$

Fano factor and the effective charge

Note that

$$\frac{\bar{I}}{S(0)} \propto \frac{\tilde{f}_{2k}^+ - \tilde{f}_{2k-1}^-}{\tilde{f}_{2k}^+ + \tilde{f}_{2k-1}^-} \equiv \lambda$$

The efficiency of Landau-Zener processes in producing current:

$$\lambda \equiv \frac{\gamma}{r} = \sqrt{\frac{p_0 p_\pi}{1 + (p_0 + p_\pi - 2p_0 p_\pi)/\gamma}} \leq 1 ; \quad \lambda = \begin{cases} 1, & p_0 = p_\pi = 1 \\ 0, & p_0 = p_\pi = 0 \end{cases}$$

Fano factor $F = S(0)/2eI$

Effective charge $q = eF = 2en/\lambda \gg e$

For point contacts:

Averin & Imam (1996)

Naveh & Averin (1999)

Here $n = v_x \tau / d \gg 1$ is the number of times which a particle can fly along the Andreev level before it escapes due to inelastic scattering

For $p_0, p_\pi \rightarrow 1, \omega_J \gg \omega_0 \gg 1/\tau$

$$q = 2en \sqrt{1 + \omega_0 \tau / \pi} \gg 2en$$

CONCLUSIONS

- ❑ **The DC current and noise spectrum in quantum SINIS contacts are sensitive to non-equilibrium distribution on the Andreev levels established by:**
 - **Voltage-driven Landau-Zener inter-level transitions**
 - **Inelastic intra-level relaxation**
- ❑ **DC current can considerably exceed the critical Josephson current.**
- ❑ **The Fano factor and the effective charge are enhanced by MAR and by Landau-Zener transition probabilities.**